

FEATURES:

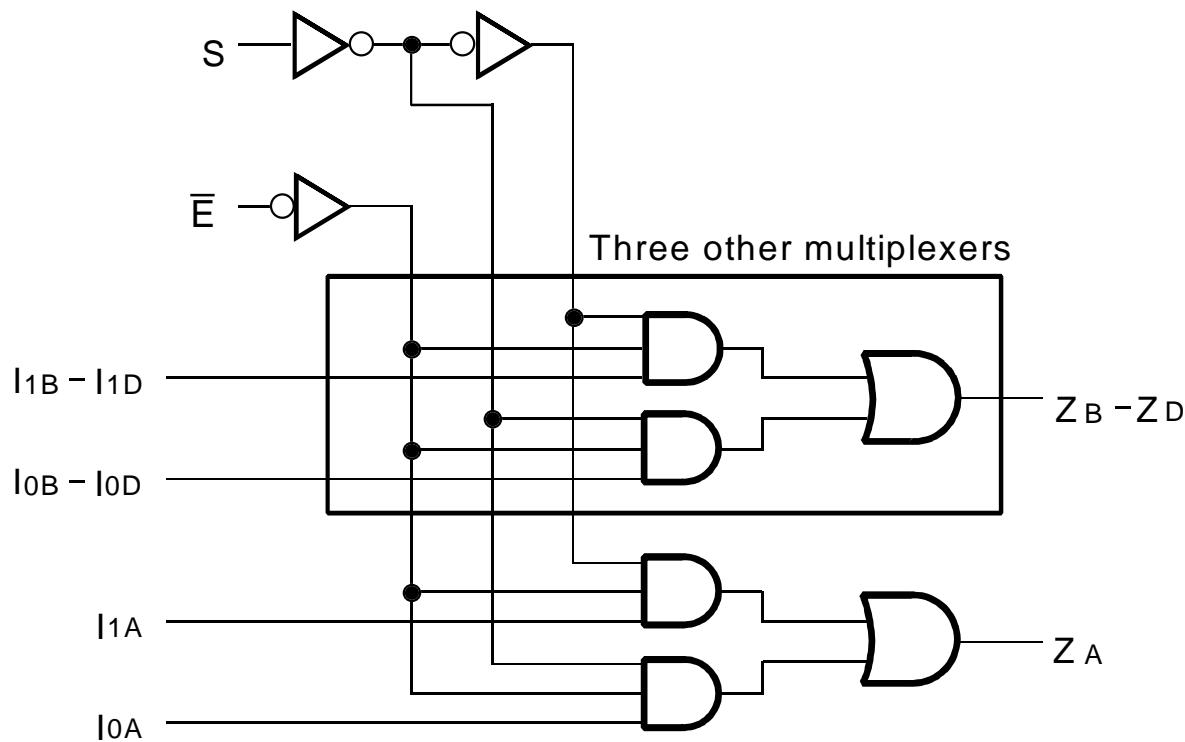
- Low input and output leakage $\leq 1\mu A$ (max.)
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3V$ (typ.)
 - $V_{OL} = 0.3V$ (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- A, C and D speed grades
- High drive outputs ($-15mA$ I_{OH} , $48mA$ I_{OL})
- Power off disable outputs permit "live insertion"
- Available in SOIC and QSOP packages

DESCRIPTION:

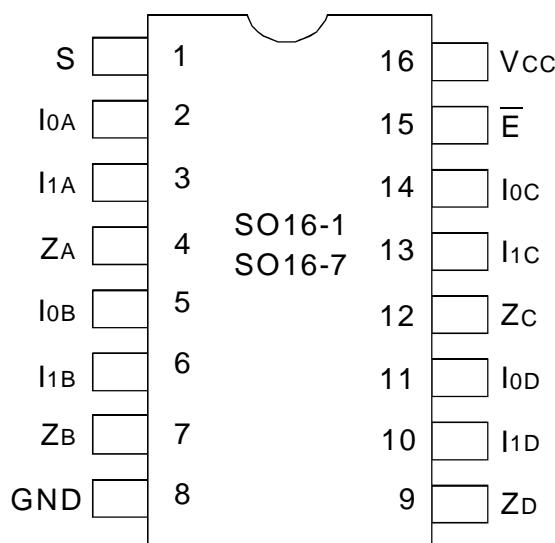
The FCT157T is a high-speed quad 2-input multiplexer built using an advanced dual metal CMOS technology. Four bits of data from two sources can be selected using the common select input. The four buffered outputs present the selected data in the true (non-inverting) form.

The FCT157T has a common, active-low, enable input. When the enable input is not active, all four outputs are held low. A common application of FCT157T is to move data from two different groups of registers to a common bus. Another application is as a function generator. The FCT157T can generate any four of the 16 different functions of two variables with one variable common.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



SOIC/ QSOP
TOP VIEW

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

| Symbol | Rating | Max. | Unit |
|----------------------------------|--------------------------------------|------------------------------|------|
| V _{TERM} ⁽²⁾ | Terminal Voltage with Respect to GND | -0.5 to +7 | V |
| V _{TERM} ⁽³⁾ | Terminal Voltage with Respect to GND | -0.5 to V _{cc} +0.5 | V |
| T _{STG} | Storage Temperature | -65 to +150 | °C |
| I _{OUT} | DC Output Current | -65 to +120 | mA |

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{cc} by +0.5V unless otherwise noted.
- Inputs and V_{cc} terminals only.
- Outputs and I/O terminals only.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

| Symbol | Parameter ⁽¹⁾ | Conditions | Typ. | Max. | Unit |
|------------------|--------------------------|-----------------------|------|------|------|
| C _{IN} | Input Capacitance | V _{IN} = 0V | 6 | 10 | pF |
| C _{OUT} | Output Capacitance | V _{OUT} = 0V | 8 | 12 | pF |

NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

| Pin Names | Description |
|----------------------------------|---------------------------|
| I _{0A} -I _{0D} | Source 0 Data Inputs |
| I _{1A} -I _{1D} | Source 1 Data Inputs |
| Ē | Enable Input (Active LOW) |
| S | Select Input |
| Z _A -Z _D | Outputs |

FUNCTION TABLE⁽¹⁾

| Inputs | | | | Outputs |
|--------|---|----------------|----------------|----------------|
| Ē | S | I ₀ | I ₁ | Z _N |
| H | X | X | X | L |
| L | H | X | L | L |
| L | H | X | H | H |
| L | L | L | X | L |
| L | L | H | X | H |

NOTE:

- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-Impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial: $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 5\%$

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-----------|--------------------------------------|--|---------------------|------|---------------------|---------|---------------|
| V_{IH} | Input HIGH Level | Guaranteed Logic HIGH Level | | 2 | — | — | V |
| V_{IL} | Input LOW Level | Guaranteed Logic LOW Level | | — | — | 0.8 | V |
| I_{IH} | Input HIGH Current ⁽⁴⁾ | $V_{CC} = \text{Max.}$ | $V_I = 2.7\text{V}$ | — | — | ± 1 | μA |
| I_{IL} | Input LOW Current ⁽⁴⁾ | | $V_I = 0.5\text{V}$ | — | — | ± 1 | |
| I_{OZH} | High Impedance Output Current | $V_{CC} = \text{Max.}$ | $V_O = 2.7\text{V}$ | — | — | ± 1 | |
| I_{OZL} | (3-State Output pins) ⁽⁴⁾ | | $V_O = 0.5\text{V}$ | — | — | ± 1 | |
| I_I | Input HIGH Current ⁽⁴⁾ | $V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$ | | — | — | ± 1 | μA |
| V_{IK} | Clamp Diode Voltage | $V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$ | | — | -0.7 | -1.2 | V |
| V_H | Input Hysteresis | — | | — | 200 | — | mV |
| I_{CC} | Quiescent Power Supply Current | $V_{CC} = \text{Max.}, V_{IN} = \text{GND or } V_{CC}$ | | — | 0.01 | 1 | mA |

OUTPUT DRIVE CHARACTERISTICS

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-----------|---|---|-------------------------|------|---------------------|---------|---------------|
| V_{OH} | Output HIGH Voltage | $V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL} | $I_{OH} = -8\text{mA}$ | 2.4 | 3.3 | — | V |
| | | | $I_{OH} = -15\text{mA}$ | 2 | 3 | — | V |
| V_{OL} | Output LOW Voltage | $V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL} | $I_{OL} = 48\text{mA}$ | — | 0.3 | 0.5 | V |
| I_{OS} | Short Circuit Current | $V_{CC} = \text{Max.}, V_O = \text{GND}$ ⁽³⁾ | | -60 | -120 | -225 | mA |
| I_{OFF} | Input/Output Power Off Leakage ⁽⁵⁾ | $V_{CC} = 0\text{V}, V_{IN}$ or $V_O \leq 4.5\text{V}$ | | — | — | ± 1 | μA |

NOTES:

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at $V_{CC} = 5.0\text{V}$, $+25^\circ\text{C}$ ambient.
3. Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
4. The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^\circ\text{C}$.
5. This parameter is guaranteed but not tested.

POWER SUPPLY CHARACTERISTICS

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|------------------|---|--|--|-----|--------------------|---------------------|------|------------|
| ΔI_{CC} | Quiescent Power Supply Current TTL Inputs HIGH | V _{CC} = Max. V _{IN} = 3.4 ⁽³⁾ | | | — | 0.5 | 2 | mA |
| I _{CCD} | Dynamic Power Supply Current ⁽⁴⁾ | V _{CC} = Max. Outputs Open \bar{E} = GND One Bit Toggling 50% Duty Cycle | | | — | 0.15 | 0.25 | mA/ MHz |
| I _C | Total Power Supply Current ⁽⁶⁾ | V _{CC} = Max. Outputs Open f_0 = 10MHz 50% Duty Cycle \bar{E} = GND One Bit Toggling | V _{IN} = V _{CC} V _{IN} = GND | — | 1.5 | 3.5 | mA | |
| | | V _{IN} = 3.4 V _{IN} = GND | — | 1.8 | 4.5 | | | |
| | | V _{IN} = V _{CC} V _{IN} = GND | — | 1.5 | 3.5 ⁽⁵⁾ | | | |
| | | V _{IN} = 3.4 V _{IN} = GND | — | 2.5 | 7.5 ⁽⁵⁾ | | | |

NOTES:

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at V_{CC} = 5.0V, +25°C ambient.

3. Per TTL driven input (V_{IN} = 3.4V); all other inputs at V_{CC} or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.

5. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.

6. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$

$$I_C = I_{CC} + \Delta I_{CC} D_{HNT} + I_{CCD} (f_0 N_0)$$

I_{CC} = Quiescent Current

ΔI_{CC} = Power Supply Current for a TTL High Input (V_{IN} = 3.4V)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current Caused by an Output Transition Pair (HLH or LHL)

f_0 = Output Frequency

N_O = Number of Outputs at f_0

All currents are in millamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

| Symbol | Parameter | Condition ⁽¹⁾ | FCT157T | | FCT157AT | | FCT157CT | | FCT157DT | | Unit |
|------------------------|---|--|---------------------|------|---------------------|------|---------------------|------|---------------------|------|------|
| | | | Min. ⁽²⁾ | Max. | |
| t_{PLH} t_{PHL} | Propagation Delay I_n to Z _N | C _L = 50pF R _L = 500Ω | 1.5 | 6 | 1.5 | 5 | 1.5 | 4.3 | 1.5 | 3.9 | ns |
| | | | 1.5 | 10.5 | 1.5 | 6 | 1.5 | 4.8 | 1.5 | 4.4 | ns |
| | | | 1.5 | 10.5 | 1.5 | 7 | 1.5 | 5.2 | 1.5 | 4.6 | ns |

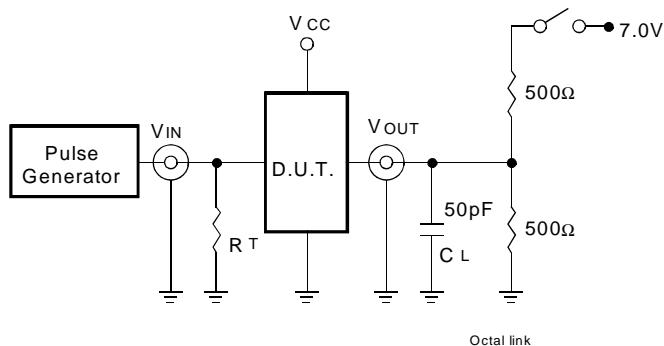
NOTES:

1. See test circuits and waveforms.

2. Minimum limits are guaranteed but not tested on Propagation Delay.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

| Test | Switch |
|-----------------|--------|
| Open Drain | Closed |
| Disable Low | |
| Enable Low | |
| All Other Tests | Open |

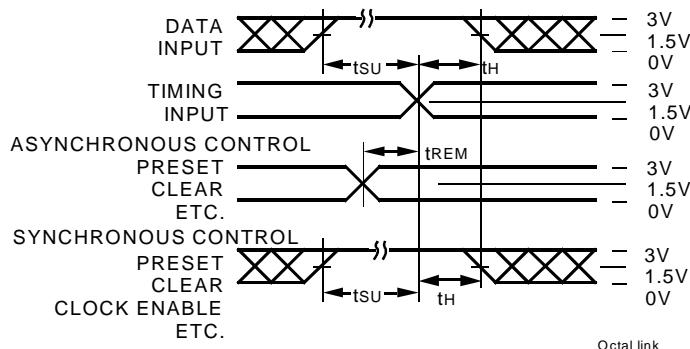
8-link

DEFINITIONS:

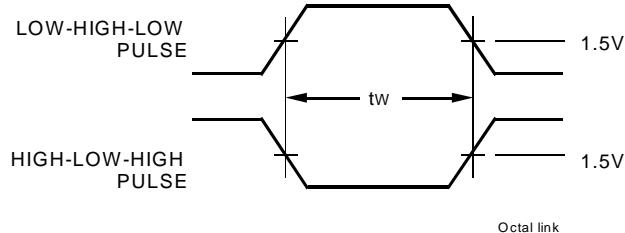
CL = Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to Zout of the Pulse Generator.

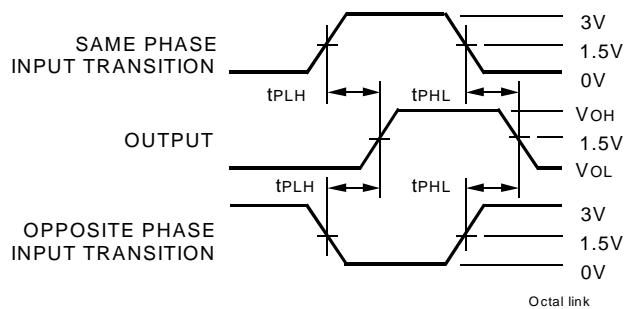
SET-UP, HOLD, AND RELEASE TIMES



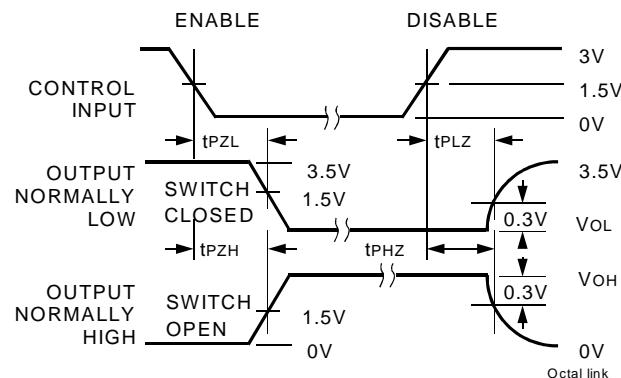
PULSE WIDTH



PROPAGATION DELAY



ENABLE AND DISABLE TIMES



NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$

ORDERING INFORMATION

IDT XX FCT XXXX X

Temperature Range

Device Type

Package

SO Small Outline IC (300 mil) (SO16-1)
Q Quarter-size Small Outline Package (SO16-7)

157T Quad 2-Input Multiplexer
157AT
157CT
157DT

74 -40°C to +85°C



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